

MMFTP84K-AH

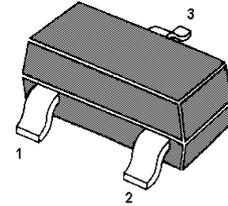
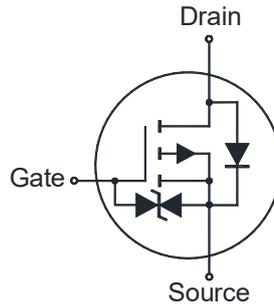
P-Channel Enhancement Mode MOSFET

Features

- AEC-Q101 Qualified
- ESD protection
- Halogen and Antimony Free(HAF), RoHS compliant

Typical ESD Protection HBM Class 1C

| Classification | Voltage Range(V) |
|----------------|------------------|
| 0A | < 125 |
| 0B | 125 to < 250 |
| 1A | 250 to < 500 |
| 1B | 500 to < 1000 |
| 1C | 1000 to < 2000 |
| 2 | 2000 to < 4000 |
| 3A | 4000 to < 8000 |
| 3B | ≥ 8000 |



1. Gate 2. Source 3. Drain
TO-236 Plastic Package

Applications

- Portable appliances

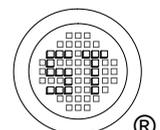
Absolute Maximum Ratings (at $T_a = 25^\circ\text{C}$ unless otherwise specified)

| Parameter | Symbol | Value | Unit |
|---|-----------------|--|--------------------|
| Drain-Source Voltage | $-V_{DS}$ | 60 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current | $-I_D$ | 180 | mA |
| Peak Drain Current, Pulsed ¹⁾ | $-I_{DM}$ | 700 | mA |
| Power Dissipation ²⁾ | P_D | 225 | mW |
| Thermal Resistance from Junction to Ambient | $R_{\theta JA}$ | 556 ²⁾ 265 ³⁾ | $^\circ\text{C/W}$ |
| Operating Junction Temperature Range | T_j | - 55 to + 150 | $^\circ\text{C}$ |
| Storage Temperature Range | T_{stg} | - 55 to + 150 | $^\circ\text{C}$ |

¹⁾ Pulse Test: Pulse Width $\leq 100 \mu\text{s}$, Duty Cycle $\leq 2\%$, Repetitive rating, pulse width limited by junction temperature $T_{j(\text{MAX})} = 150^\circ\text{C}$.

²⁾ Device mounted on FR-4 substrate PC board, with minimum recommended pad layout.

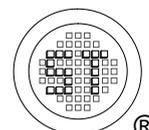
³⁾ Device mounted on FR-4 substrate PC board, 2oz copper, with 1-inch square copper plate.



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Characteristics at $T_a = 25^\circ\text{C}$ unless otherwise specified

| Parameter | Symbol | Min. | Typ. | Max. | Unit |
|---|----------------|--------|--------|----------|---------------|
| STATIC PARAMETERS | | | | | |
| Drain-Source Breakdown Voltage at $-I_D = 250 \mu\text{A}$ | $-V_{(BR)DSS}$ | 60 | - | - | V |
| Zero Gate Voltage Drain Current at $-V_{DS} = 25 \text{ V}$ at $-V_{DS} = 60 \text{ V}$ | $-I_{DSS}$ | - - | - - | 0.1 1 | μA |
| Gate-Source Leakage at $V_{GS} = \pm 20 \text{ V}$ | I_{GSS} | - | - | ± 10 | μA |
| Gate-Source Threshold Voltage at $V_{DS} = V_{GS}$, $-I_D = 250 \mu\text{A}$ | $-V_{GS(th)}$ | 0.9 | - | 2 | V |
| Drain-Source On-State Resistance at $-V_{GS} = 5 \text{ V}$, $-I_D = 0.1 \text{ A}$ | $R_{DS(on)}$ | - | 2.6 | 10 | Ω |
| DYNAMIC PARAMETERS | | | | | |
| Forward Transconductance at $-V_{DS} = 25 \text{ V}$, $-I_D = 0.1 \text{ A}$, $f = 1 \text{ KHz}$ | g_{fs} | 50 | - | - | mS |
| Input Capacitance at $V_{GS} = 0 \text{ V}$, $-V_{DS} = 30 \text{ V}$, $f = 1 \text{ MHz}$ | C_{iss} | - | 38 | - | pF |
| Output Capacitance at $V_{GS} = 0 \text{ V}$, $-V_{DS} = 30 \text{ V}$, $f = 1 \text{ MHz}$ | C_{oss} | - | 9 | - | pF |
| Reverse Transfer Capacitance at $V_{GS} = 0 \text{ V}$, $-V_{DS} = 30 \text{ V}$, $f = 1 \text{ MHz}$ | C_{rss} | - | 6 | - | pF |
| Total Gate Charge at $-V_{DS} = 25 \text{ V}$, $-V_{GS} = 4.5 \text{ V}$, $-I_D = 0.1 \text{ A}$ | Q_g | - | 1.1 | - | nC |
| Gate Source Charge at $-V_{DS} = 25 \text{ V}$, $-V_{GS} = 4.5 \text{ V}$, $-I_D = 0.1 \text{ A}$ | Q_{gs} | - | 0.3 | - | nC |
| Gate Drain Charge at $-V_{DS} = 25 \text{ V}$, $-V_{GS} = 4.5 \text{ V}$, $-I_D = 0.1 \text{ A}$ | Q_{gd} | - | 0.2 | - | nC |
| Turn-On Rise Time at $-V_{DS} = 25 \text{ V}$, $-V_{GS} = 10 \text{ V}$, $-I_D = 0.1 \text{ A}$, $R_g = 6.8 \Omega$ | $t_{d(on)}$ | - | 14 | - | ns |
| Turn-On Rise Time at $-V_{DS} = 25 \text{ V}$, $-V_{GS} = 10 \text{ V}$, $-I_D = 0.1 \text{ A}$, $R_g = 6.8 \Omega$ | t_r | - | 4 | - | ns |
| Turn-Off Delay Time at $-V_{DS} = 25 \text{ V}$, $-V_{GS} = 10 \text{ V}$, $-I_D = 0.1 \text{ A}$, $R_g = 6.8 \Omega$ | $t_{d(off)}$ | - | 15 | - | ns |
| Turn-Off Fall Time at $-V_{DS} = 25 \text{ V}$, $-V_{GS} = 10 \text{ V}$, $-I_D = 0.1 \text{ A}$, $R_g = 6.8 \Omega$ | t_f | - | 77 | - | ns |
| Body-Diode PARAMETERS | | | | | |
| Drain-Source Diode Forward Voltage at $-I_S = 0.5 \text{ A}$ | $-V_{SD}$ | - | - | 1.2 | V |
| Body Diode Reverse Recovery Time at $-I_S = 0.1 \text{ A}$, $di/dt = 100 \text{ A} / \mu\text{s}$ | t_{rr} | - | 60 | - | ns |
| Body Diode Reverse Recovery Charge at $-I_S = 0.1 \text{ A}$, $di/dt = 100 \text{ A} / \mu\text{s}$ | Q_{rr} | - | 58 | - | nC |



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Electrical Characteristics Curves

Fig. 1 Typical Output Characteristic

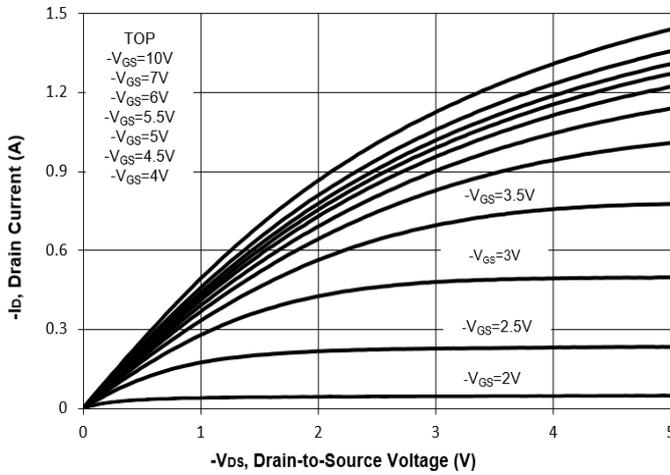


Fig. 2 Typical Transfer Characteristic

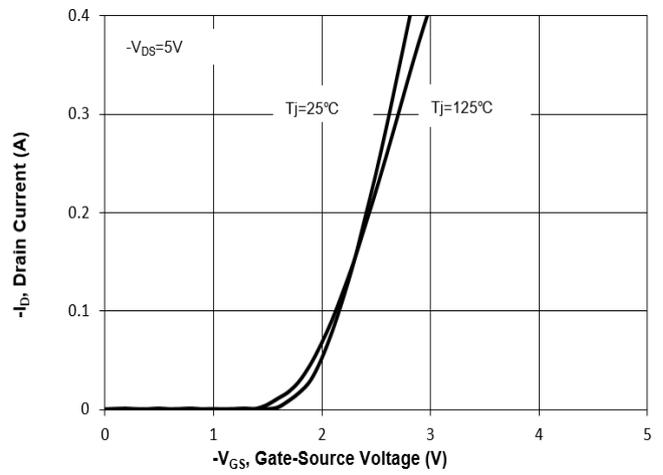


Fig. 3 on-Resistance vs. Gate Voltage

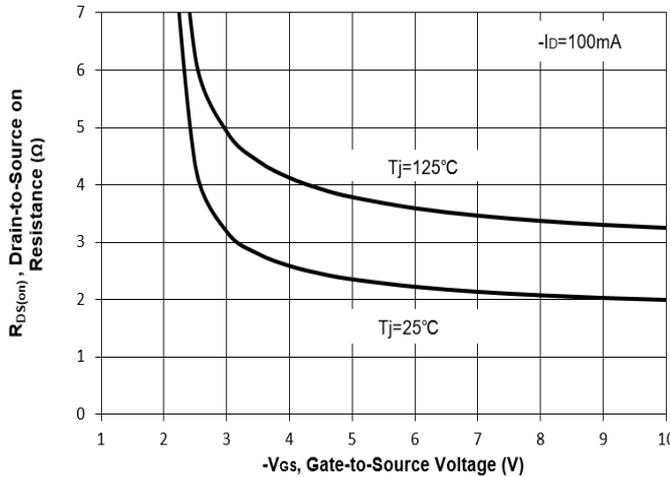


Fig. 4 on-Resistance vs. T_j

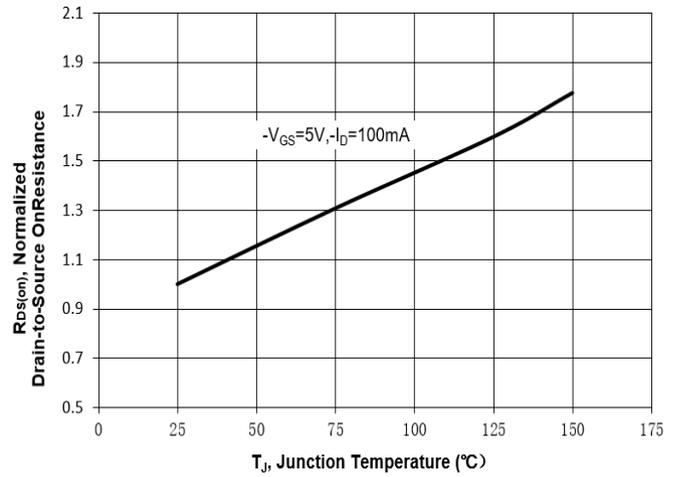


Fig. 5 On-Resistance vs. Drain Current

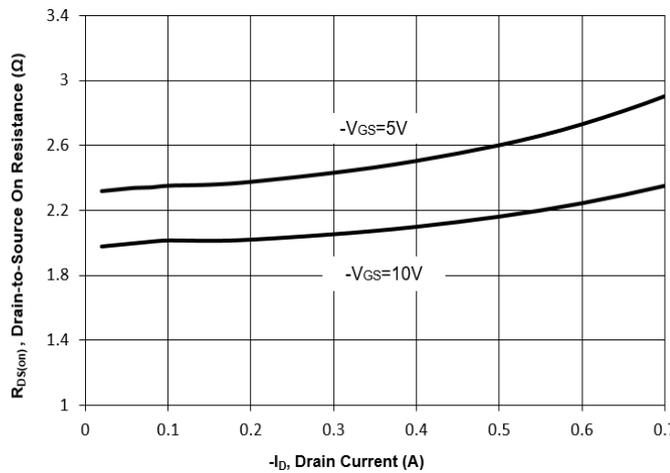
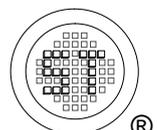
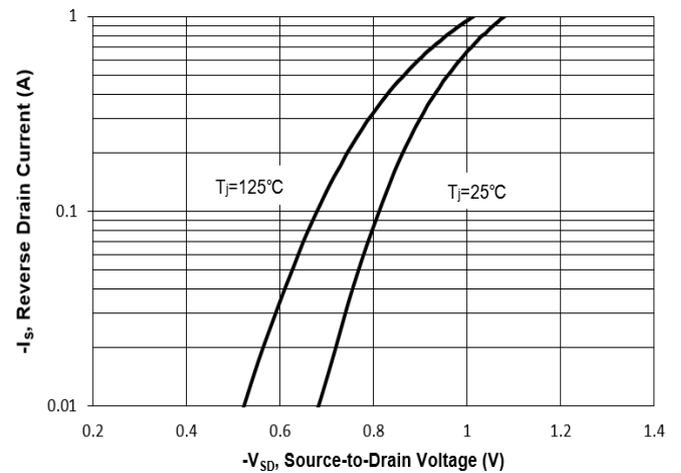


Fig. 6 Typical Forward Characteristic



Electrical Characteristics Curves

Fig. 7 $V_{(BR)DSS}$ vs. Junction Temperature

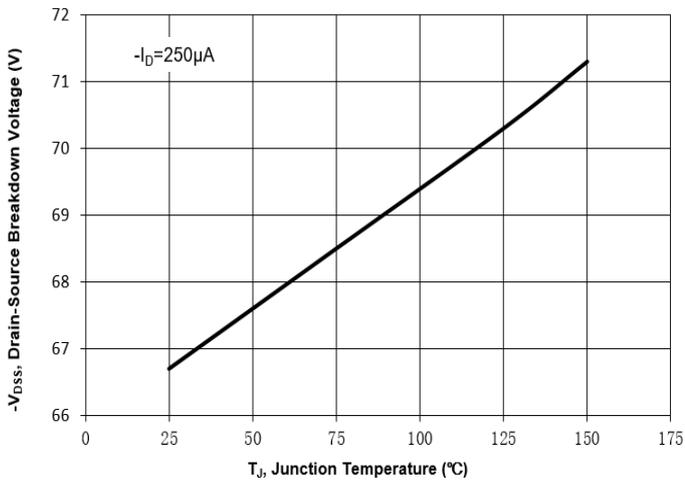


Fig. 8 Gate Threshold Variation vs. T_J

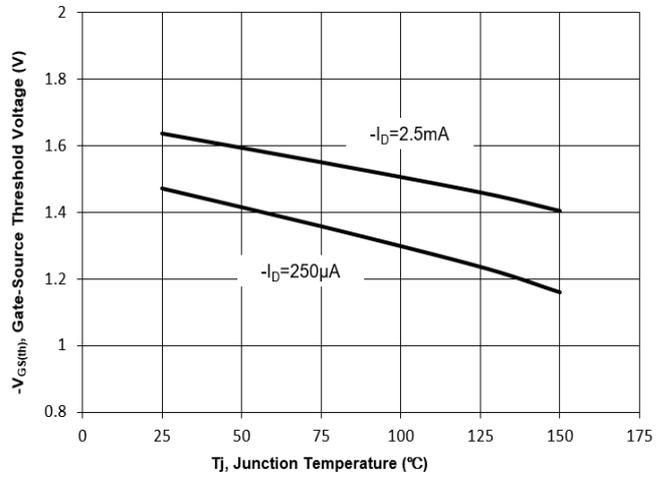


Fig. 9 Typical Junction Capacitance

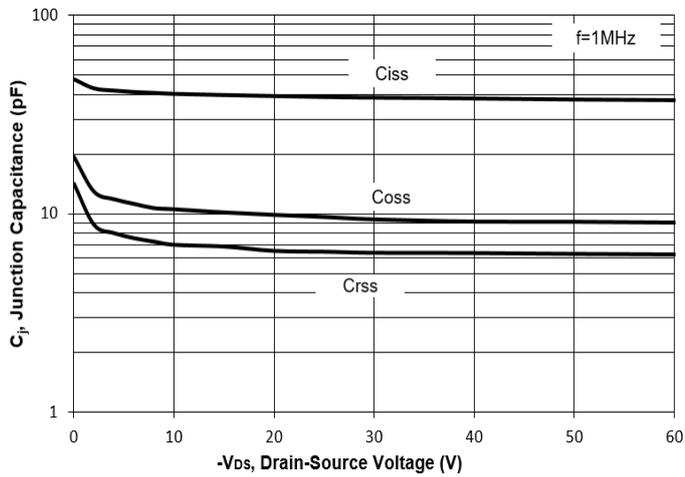


Fig. 10 Gate Charge

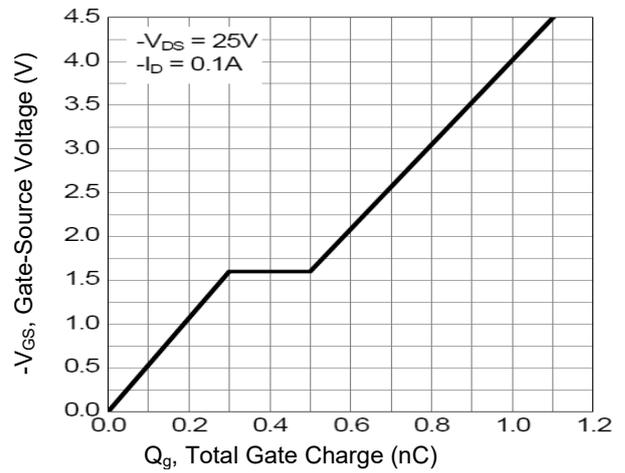
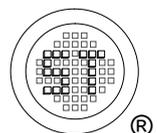
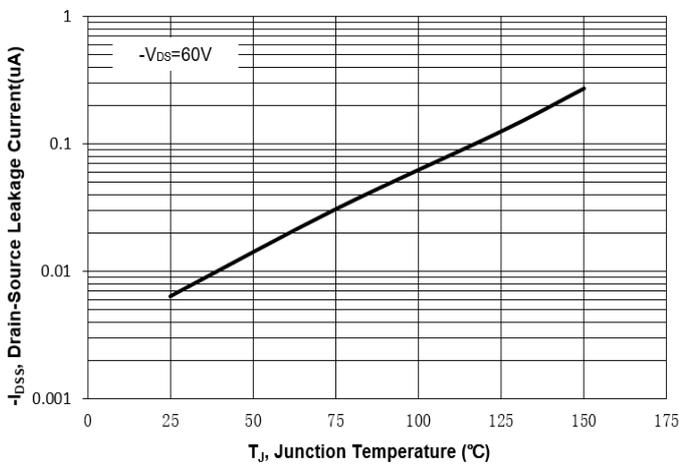


Fig. 11 Drain-Source Leakage Current vs. T_J



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Test Circuits

Fig.1-1 Switching times test circuit

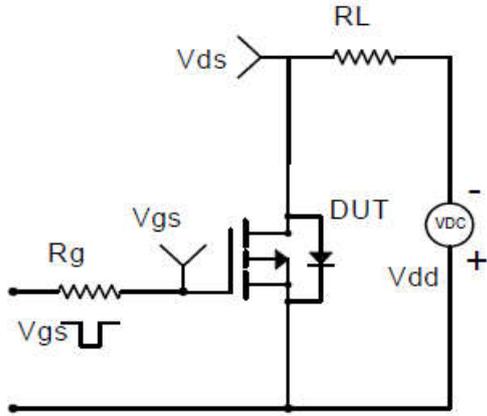


Fig.1-2 Switching Waveform

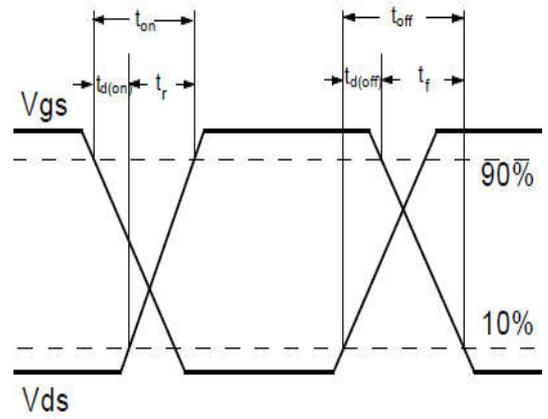


Fig.2-1 Gate charge test circuit

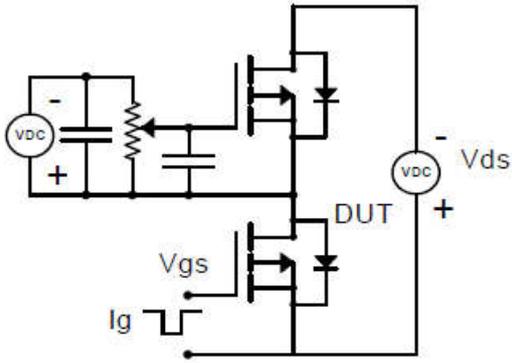
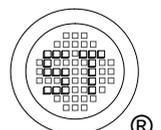
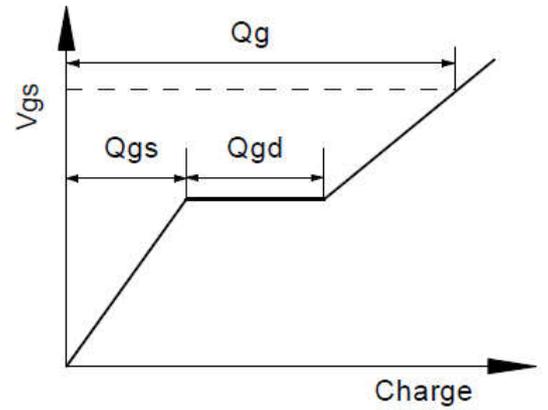


Fig.2-2 Gate charge waveform

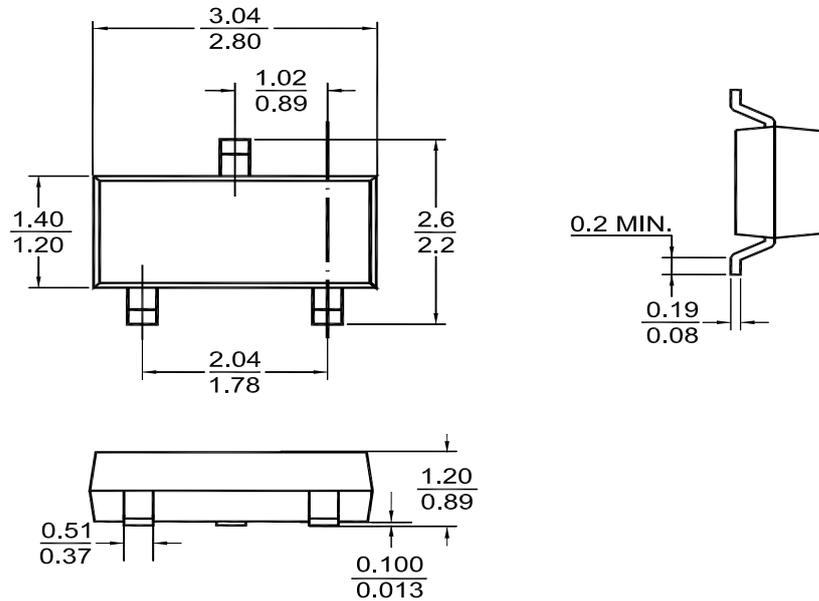


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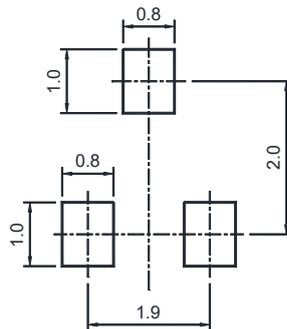
PACKAGE OUTLINE

Plastic surface mounted package (Dimensions in mm)

TO-236



Recommended Soldering Footprint



Packing information

| Package | Tape Width (mm) | Pitch | | Reel Size | | Per Reel Packing Quantity |
|---------|-----------------|---------|---------------|-----------|------|---------------------------|
| | | mm | inch | mm | inch | |
| TO-236 | 8 | 4 ± 0.1 | 0.157 ± 0.004 | 178 | 7 | 3,000 |

Marking information

- "VY" = Part No.
- "•" = HAF (Halogen and Antimony Free)
- "YM" = Date Code Marking
- "Y" = Year
- "M" = Month
- Font type: Arial

